Optical Engineering

OpticalEngineering.SPIEDigitalLibrary.org

Study of Cr/Sc-based multilayer reflecting mirrors using soft x-ray reflectivity and standing wave-enhanced x-ray fluorescence (Erratum)

Meiyi Wu
Catherine Burcklen
Jean-Michel André
Karine Le Guen
Angelo Giglia
Konstantin Koshmak
Stefano Nannarone
Françoise Bridou
Evgueni Meltchakov
Sébastien de Rossi
Franck Delmotte
Philippe Jonnard

SPIE.

Meiyi Wu, Catherine Burcklen, Jean-Michel André, Karine Le Guen, Angelo Giglia, Konstantin Koshmak, Stefano Nannarone, Françoise Bridou, Evgueni Meltchakov, Sébastien de Rossi, Franck Delmotte, Philippe Jonnard, "Study of Cr/Sc-based multilayer reflecting mirrors using soft x-ray reflectivity and standing wave-enhanced x-ray fluorescence (Erratum)," *Opt. Eng.* **56**(11), 119801 (2017), doi: 10.1117/1.OE.56.11.119801.

Study of Cr/Sc-based multilayer reflecting mirrors using soft x-ray reflectivity and standing wave-enhanced x-ray fluorescence (Erratum)

Meiyi Wu,^{a,b} Catherine Burcklen,^c Jean-Michel André,^{a,b} Karine Le Guen,^{a,b} Angelo Giglia,^d Konstantin Koshmak,^d Stefano Nannarone,^d Françoise Bridou,^c Evgueni Meltchakov,^c Sébastien de Rossi,^c Franck Delmotte,^c and Philippe Jonnard^{a,b}

^aSorbonne Universités, UPMC UnivParis 06, Laboratoire de Chimie Physique—Matière et Rayonnement, Paris, France

^bCNRS UMR 7614, Laboratoire de Chimie Physique—Matière et Rayonnement, Paris, France

^cUniversité Paris-Saclay, Institut d'Optique Graduate School, Laboratoire Charles Fabry, CNRS, Palaiseau Cedex, France

^dCNR, Istituto Officina Materiali, Trieste, Italy

[DOI: [10.1117/1.OE.56.11.119801](https://doi.org/10.1117/1.OE.56.11.119801)]

This article [*Opt. Eng.* **56**(11), 117101 (2017)] was originally published on 1 November 2017 with an error in the author list. The 11th author's name was misspelled. It is correctly spelled Franck Delmotte, as shown here.

The paper was corrected online on 7 November 2017. It appears correctly in print.